
**Ocenjevanje gostote moči izpostavljenosti človeka radiofrekvenčnim poljem
brežžičnih naprav v neposredni bližini glave in telesa (frekvenčno območje 6 GHz
do 300 GHz) - 1. del: Merilni postopek**

Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body (frequency range of 6 GHz to 300 GHz) - Part 1: Measurement procedure

Bewertung der Leistungsdichte der Exposition des Menschen gegenüber hochfrequenten Feldern von drahtlosen Geräten in unmittelbarer Nähe des Kopfes und des Körpers (Frequenzbereich von 6 GHz bis 300 GHz) - Teil 1: Messverfahren

Évaluation de la densité de puissance de l'exposition humaine aux champs radiofréquences provenant de dispositifs sans fil à proximité immédiate de la tête et du corps (plage de fréquences de 6 GHz à 300 GHz) - Partie 1: Procédure de mesure

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(IEC/IEEE 63195-1:2022)

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Menschen gegenüber hochfrequenten Feldern von
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des Körpers (Frequenzbereich von 6 GHz bis 300 GHz) -
Teil 1: Messverfahren
(IEC/IEEE 63195-1:2022)

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EN IEC/IEEE 63195-1:2023 (E)**European foreword**

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ISO/IEC 17025:2017	NOTE Harmonized as EN ISO/IEC 17025:2017 (not modified)
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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

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<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC/IEEE 62209-1528	2020	Measurement procedure for the assessment of specific absorption rate of human exposure to radio frequency fields from hand-held and body-worn wireless communication devices - Part 1528: Human models, instrumentation and procedures (Frequency range of 4 MHz to 10 GHz)	EN IEC/IEEE 62209-1528	2021
IEC/IEEE 63195-2	2022	Assessment of power density of human exposure to radio frequency fields from wireless devices in close proximity to the head and body (Frequency range of 6 GHz to 300 GHz) – Part 2: Computational procedure	EN IEC/IEEE 63195-2	2023

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Part 1: Measurement procedure**

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Partie 1: Procédure de mesure**

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